SHEET 1 OF 4 **FORM PTO-1449** U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET NO. APPLICATION NO. PATENT AND TRADEMARK DEFICE FETHE24.001CP1 10/005,186 INFORMATION DISCLOSURE STATEMENT MAY 2 2 2002 **BY APPLICANT** (USE SEVERAL SHEETS IF NECESSARY) MAY 2 0 2002 APPLICANTS Camm, et al. GROUP ARTICINITINOLOGY CENTER R3700 FILING DATE December 4, 2001

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	3,160,517	12/08/64	Jenkin		1			
	3,188,459	06/08/65	Bridwell	<b>†</b>	1			
	3,227,065	01/04/66	Litman	$\top$	7			
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			4,331,485	05/25/82	Gat						
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